

FIG. 1

(PRIOR ART)

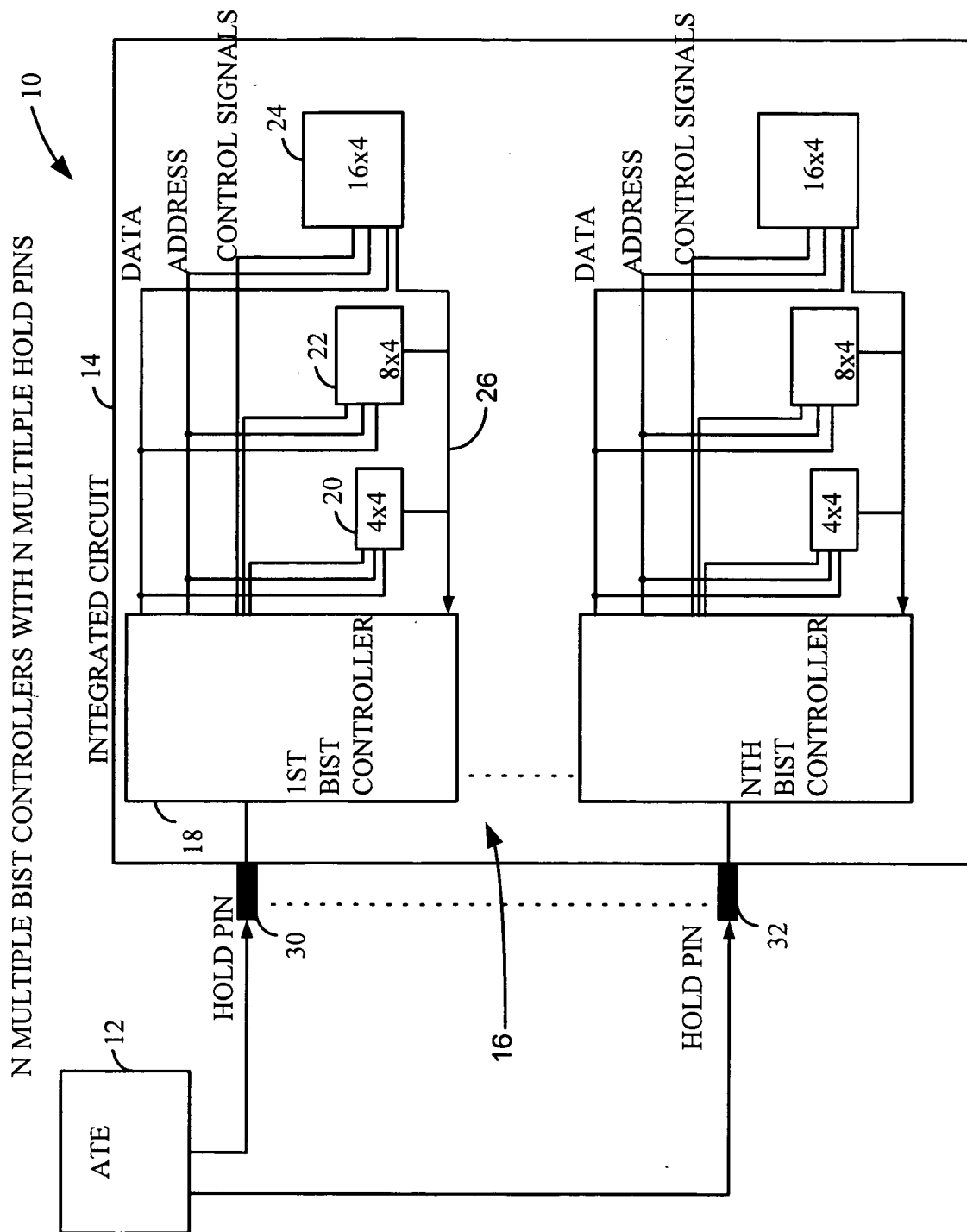


FIG. 2

TEST ON THREE MEMORIES COUPLED TO A SINGLE SEQUENTIAL BIST CONTROLLER USING THREE SEPARATE IDLE PERIODS

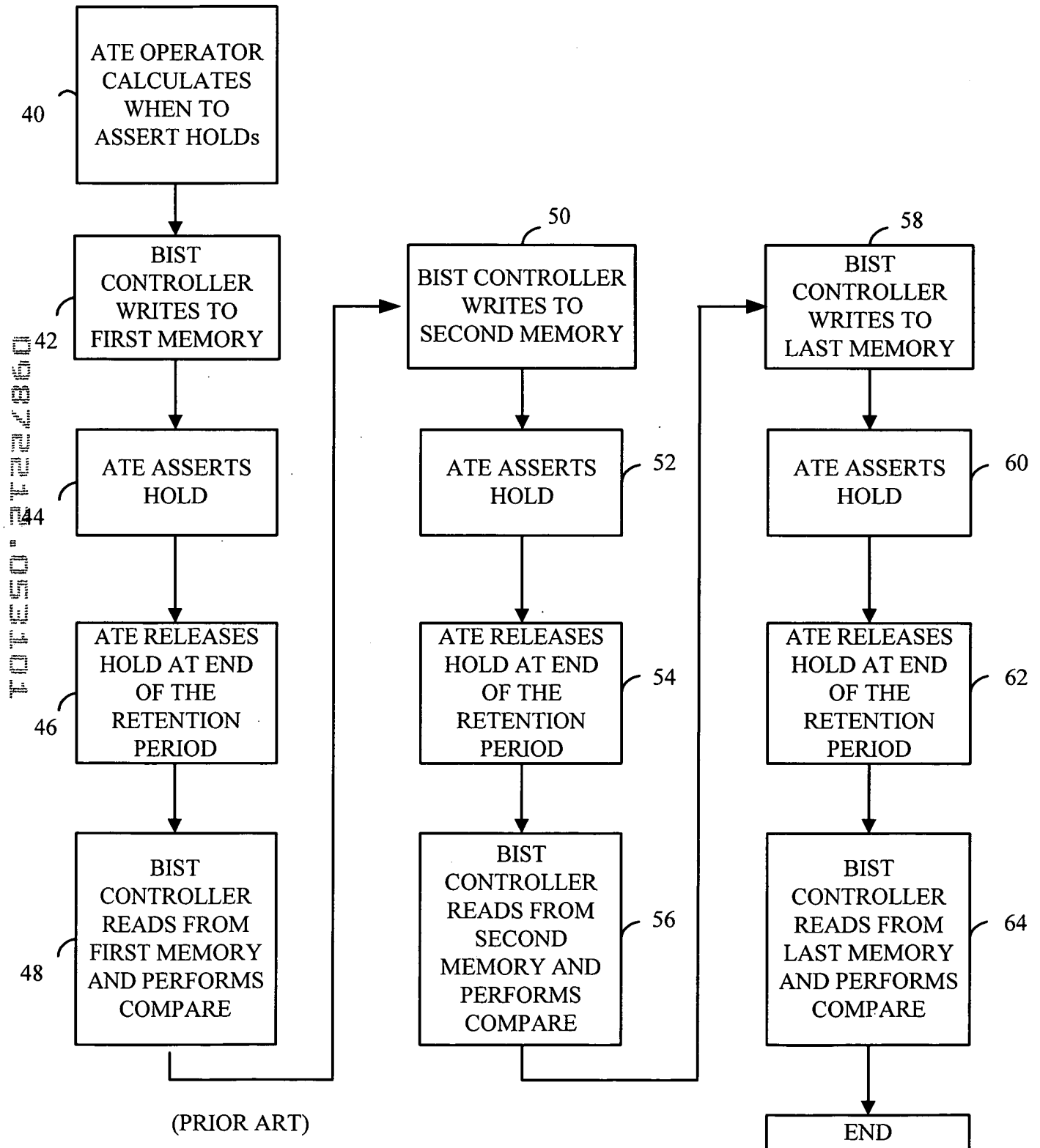


FIG. 3

N MULTIPLE BIST CONTROLLERS WITH SINGLE SYNCHRONIZE AND RESUME PINS

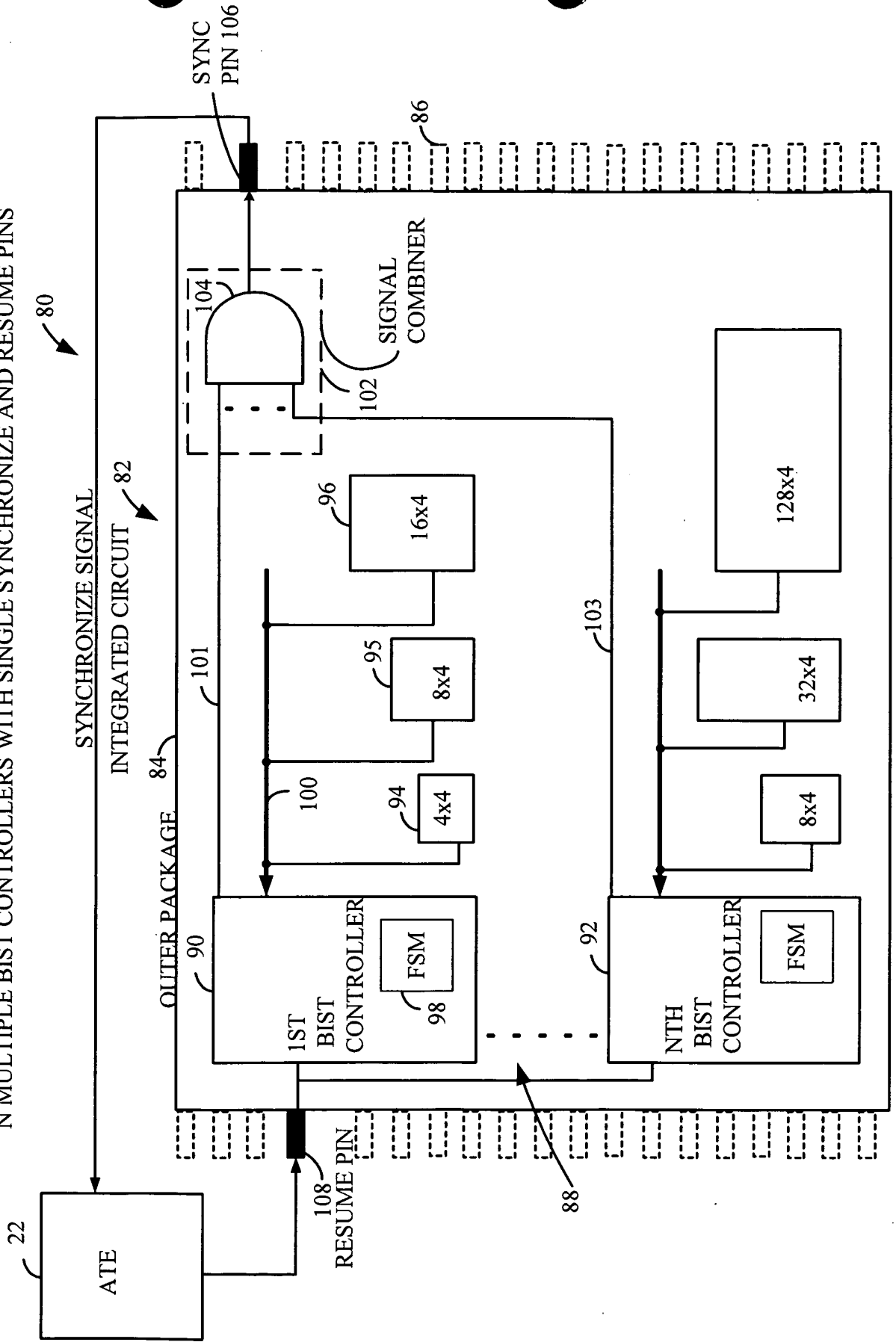
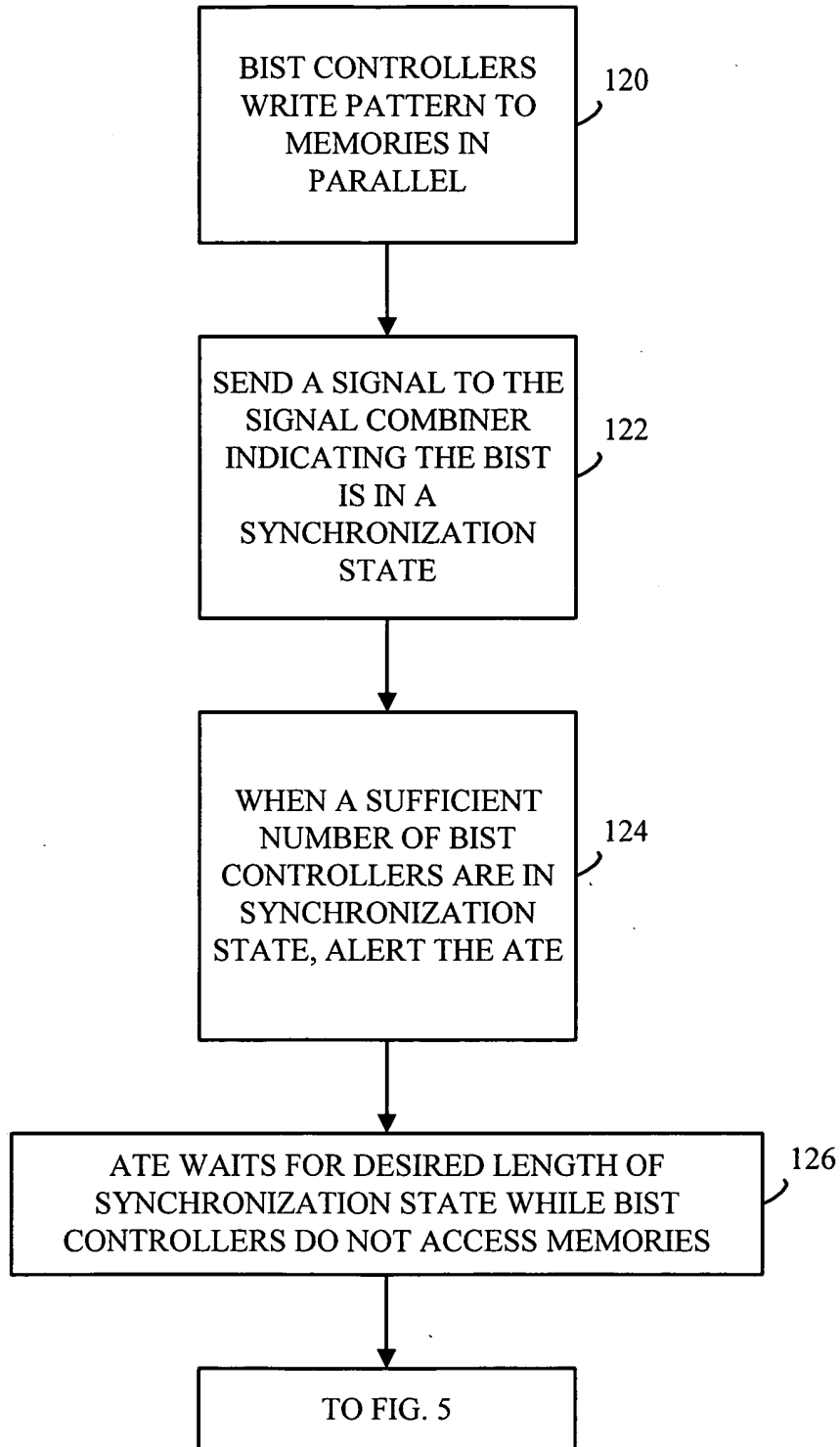


FIG. 4

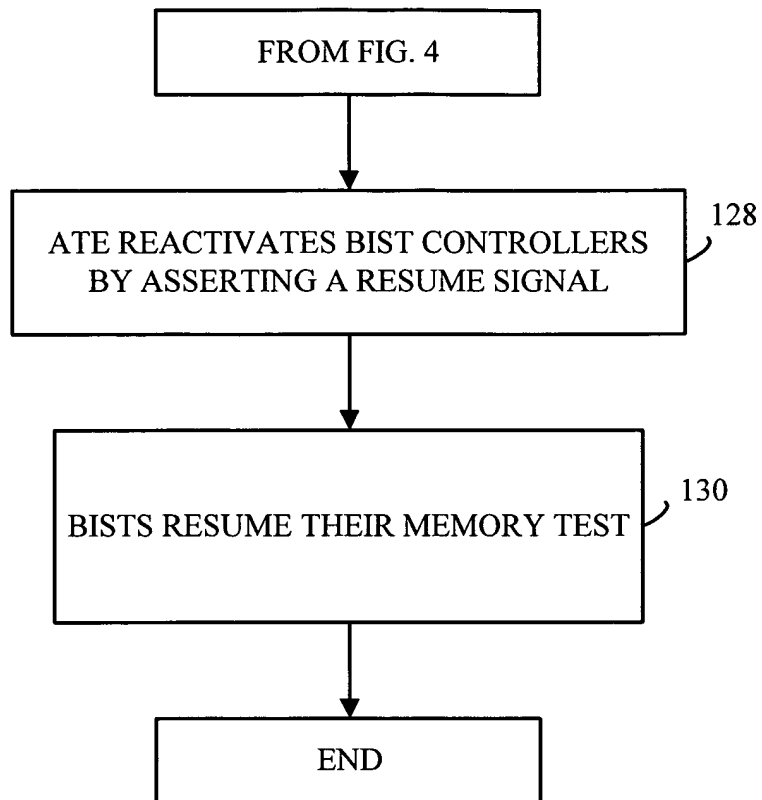
TEST OF MEMORIES WITH MULTIPLE PARALLEL BIST
CONTROLLERS USING SYNCHRONIZATION STATE



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FIG. 5

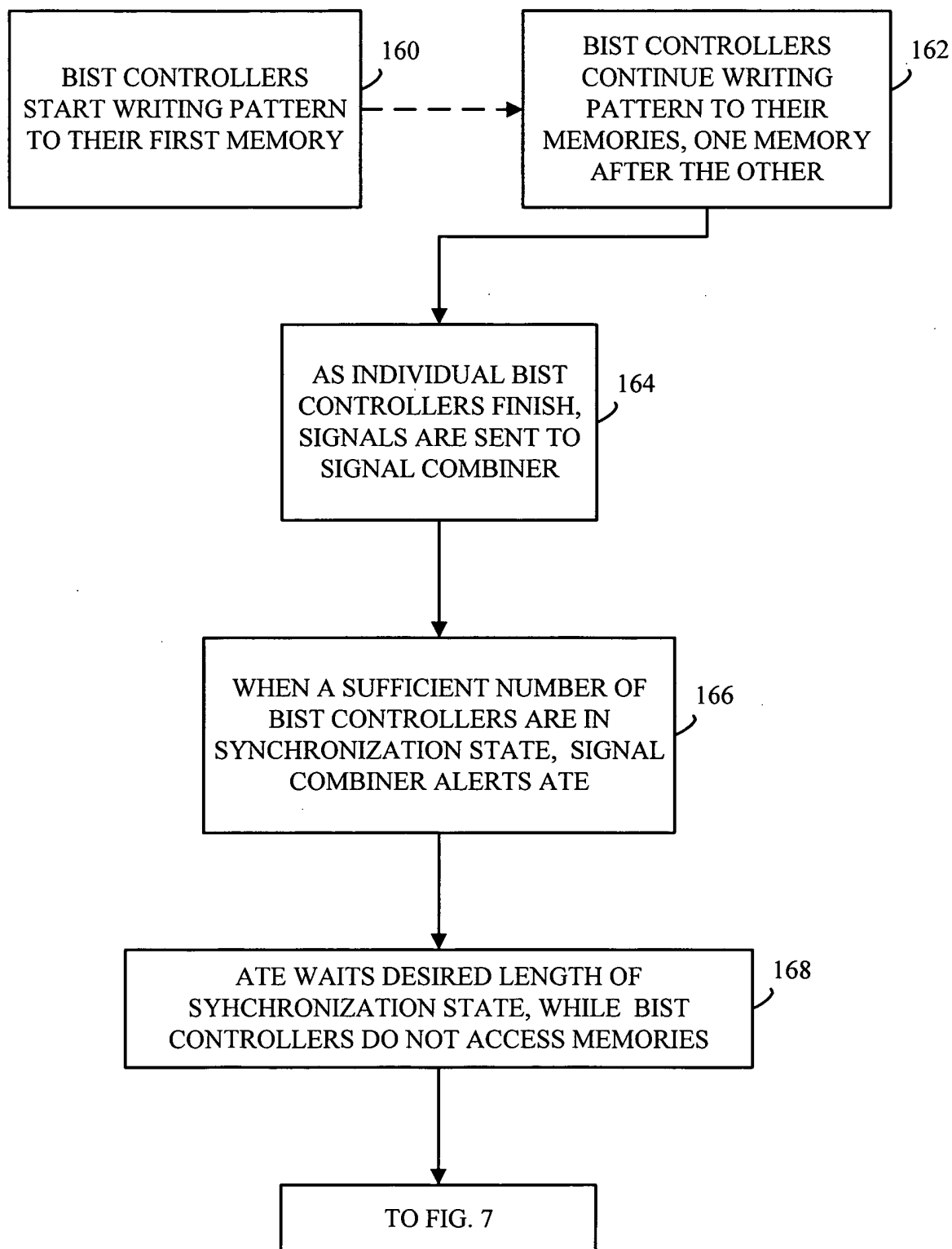
TEST OF MEMORIES WITH MULTIPLE PARALLEL BIST
CONTROLLERS USING SYNCHRONIZATION STATE (CONTINUED)



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FIG. 6

TEST OF MEMORIES WITH MULTIPLE SEQUENTIAL BIST
CONTROLLERS USING SYNCHRONIZATION STATE



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FIG. 7

TEST OF MEMORIES WITH MULTIPLE SEQUENTIAL BIST
CONTROLLERS USING SYNCHRONIZATION STATE (CONTINUED)

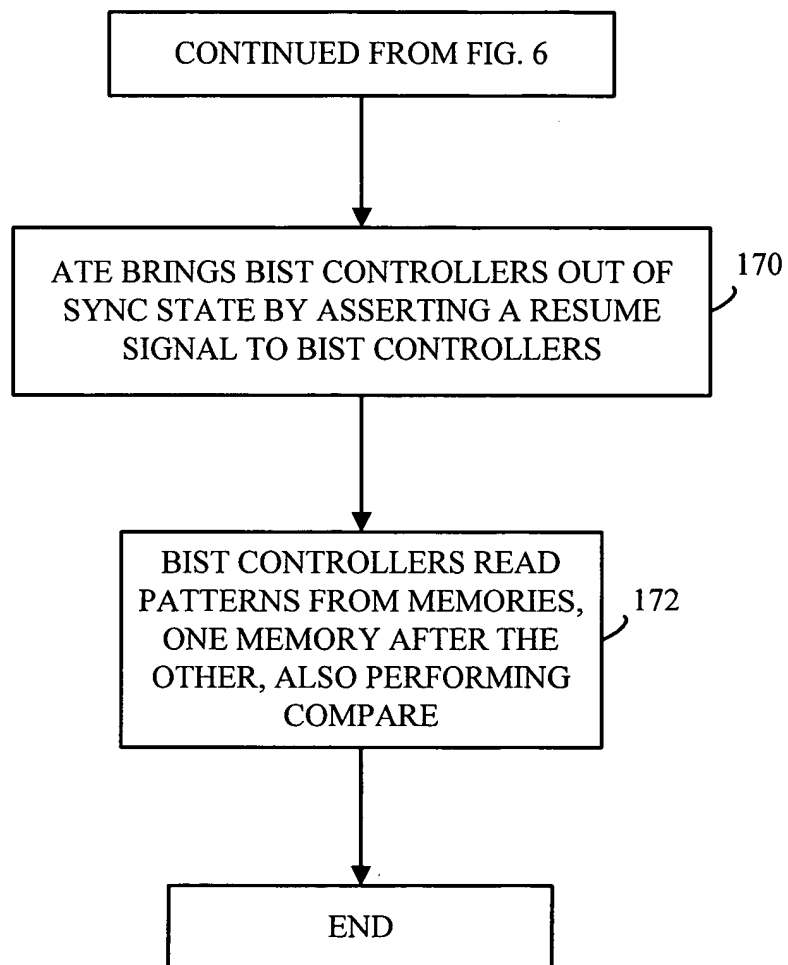


FIG. 7

FIG. 8 — BIST CONTROLLER GENERATOR

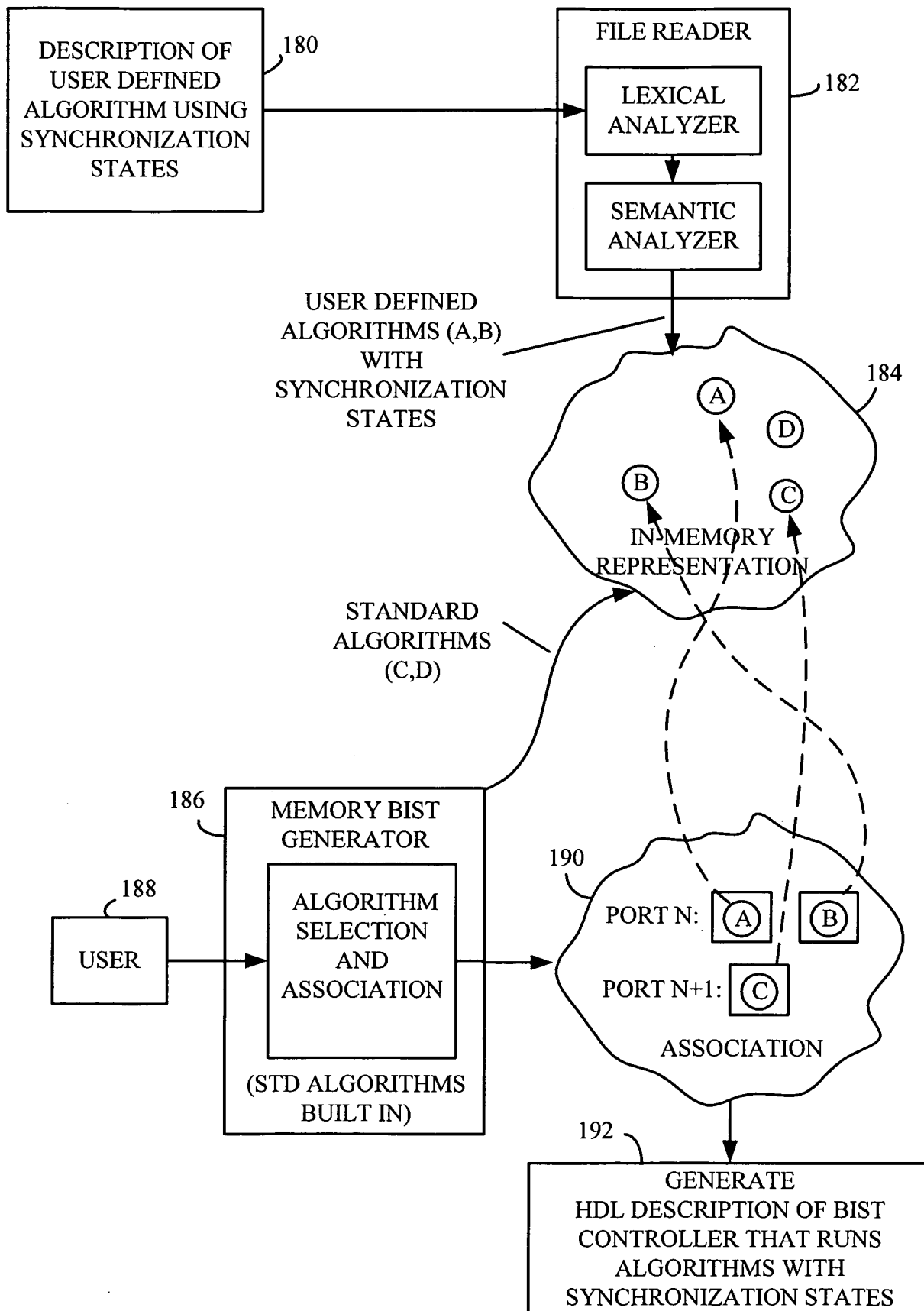
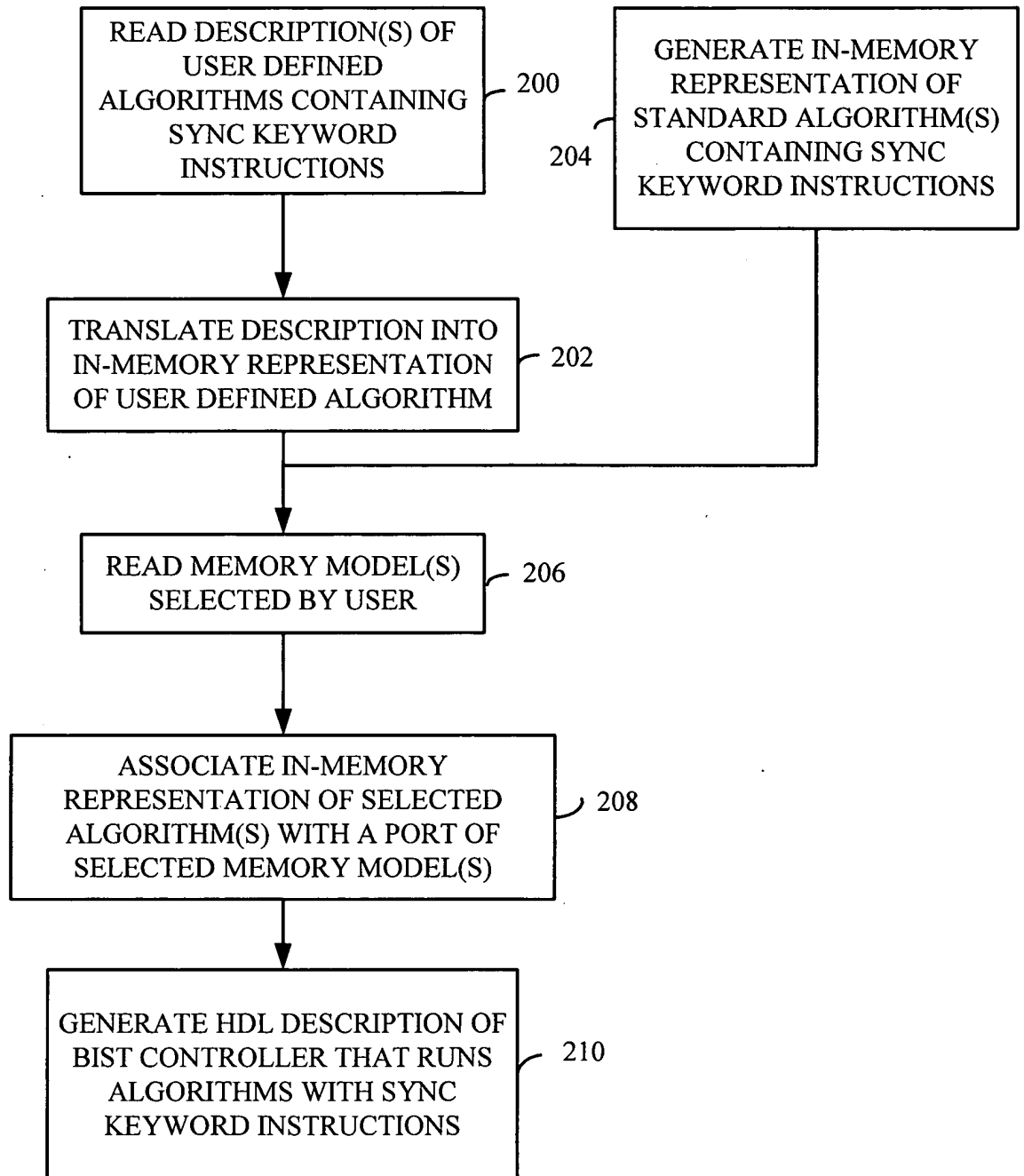


FIG. 8 - BIST CONTROLLER GENERATOR

FIG. 9

GENERATING A BIST CONTROLLER THAT RUNS USER
DEFINABLE ALGORITHMS WITH SYNC KEYWORD



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